

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Hisae SHIBUYA, et al.

Application No.: 10/672,010

Filed: September 25, 2003

For: METHOD AND APPARATUS FOR  
ANALYZING DEFECT DATA AND A  
REVIEW SYSTEM

Customer No.: 20350

Confirmation No. 7689

Examiner: Alex Kok Soon Liew

Technology Center/Art Unit: 2624

AMENDMENT

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

October 16, 2008 (e-filed)

Sir:

In response to the Office Action mailed June 16, 2008, please enter the following amendments and remarks:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 7 of this paper.